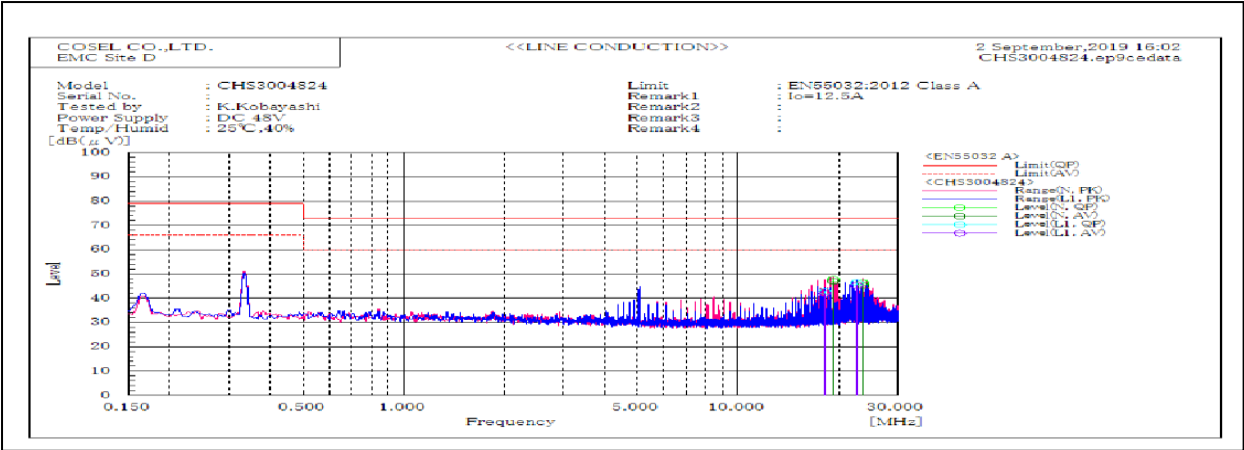
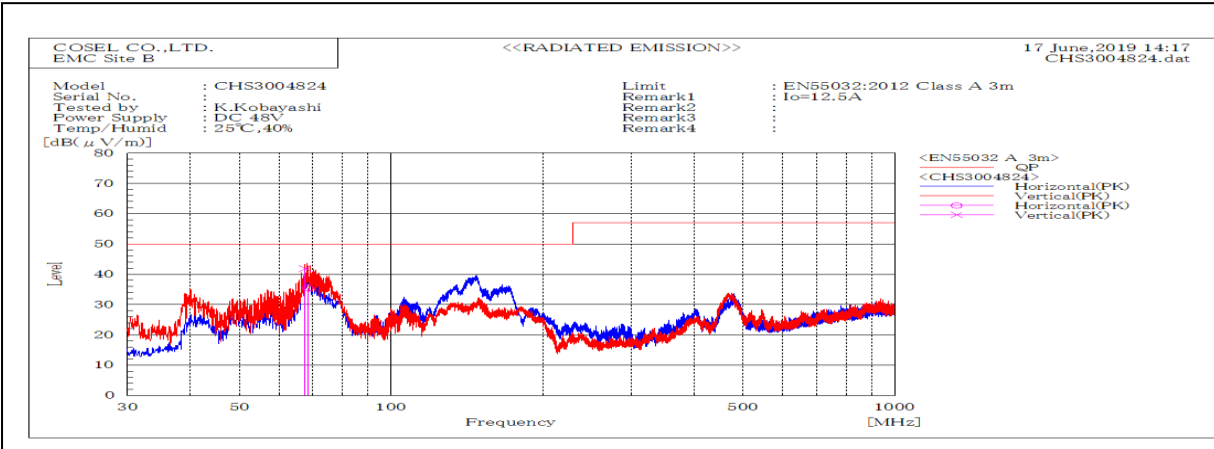


DATA SHEET		Date	02-Sep-19
Model	CHS3004824	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi



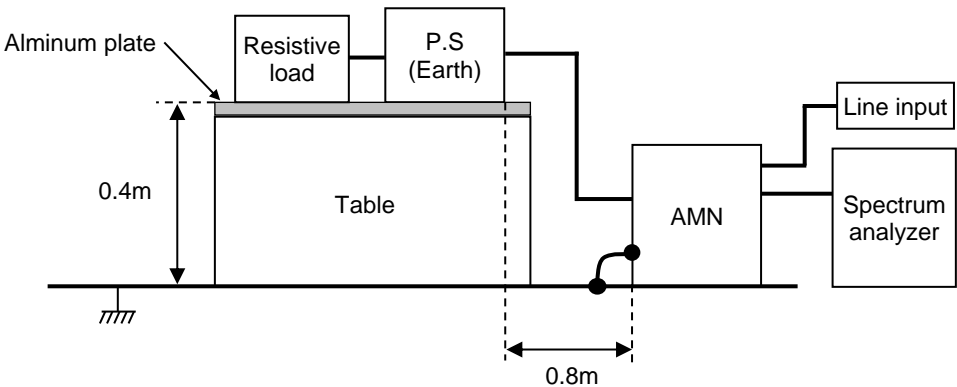
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
19.23	N	47.8	46.9	73.0	60.0	25.2	13.1	Pass	
23.61	N	46.4	45.3	73.0	60.0	26.6	14.7	Pass	
22.60	L1	46.4	45.3	73.0	60.0	26.6	14.7	Pass	
18.22	L1	42.8	41.9	73.0	60.0	30.2	18.1	Pass	



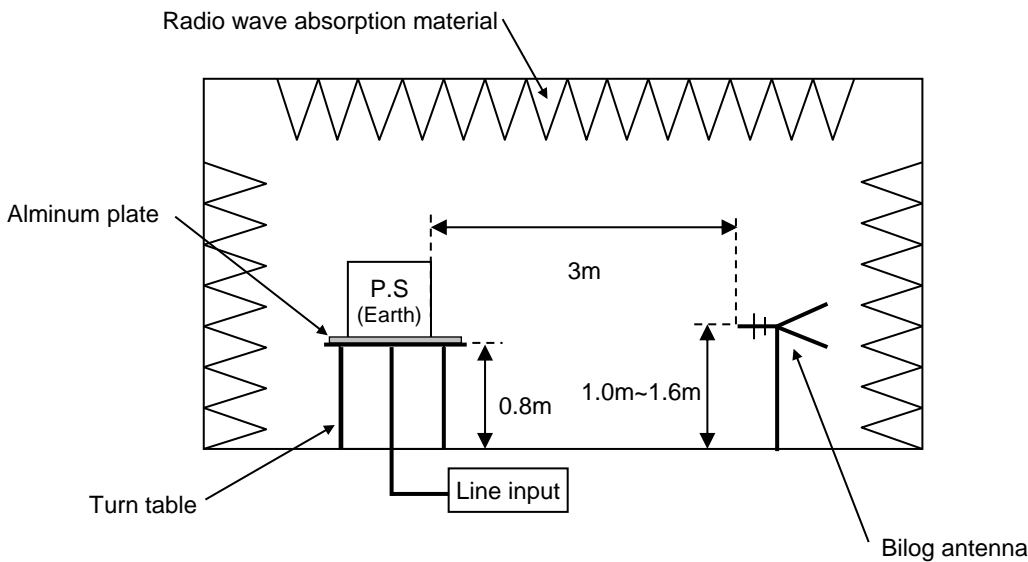
Frequency MHz	Polarization	Stability	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
68.45	H	Stable	35.5	50.0	14.5	Pass	111.6	353.8	
67.48	V	Stable	41.9	50.0	8.1	Pass	100.0	0.0	

DATA SHEET		Date	02-Sep-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name : CHS30048□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

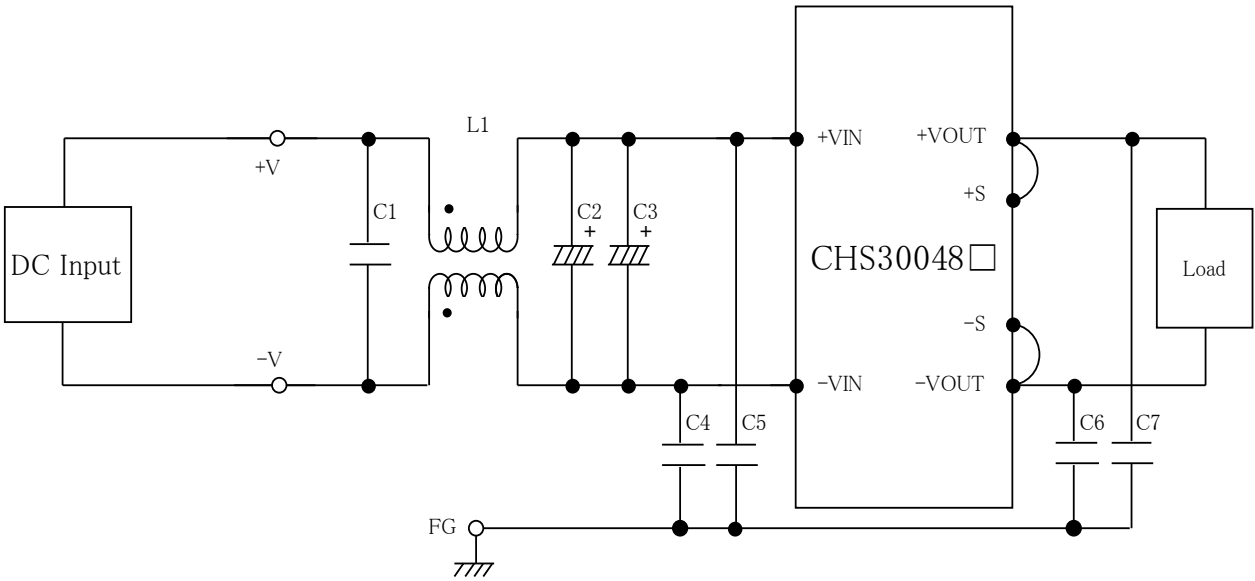


Fig.1 Testing circuitry

- L1 : 1mH SC-20-10JH (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2,C3 : 100V 100 μ F PWseries (nichicon)
- C4,C5 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
- C6,C7 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)